



STALLMAN & POLLOCK LLP
121 Spear Street, Suite 290
San Francisco, CA 94105
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In re Patent Application of: Allan Rosencwaig et al.

Atty Docket No. TWI-10820

Application No.: 09/629,407

Filed: August 1, 2000

For: MEASUREMENT OF THIN FILMS AND BARRIER LAYERS ON PATTERNED WAFERS WITH
X-RAY REFLECTOMETRY

Box NON-FEE AMENDMENT
Commissioner for Patents
Washington, D.C. 20231

Sir:

Transmittal herewith is an amendment in the above-identified application.

The fee has been calculated as shown below.

	CLAIMS REMAINING AFTER AMENDMENT		HIGHEST NO. PREVIOUSLY PAID FOR	PRESENT EXTRA	RATE	ADDITIONAL FEE
TOTAL	31	MINUS	31	0	x \$18 =	\$0
INDEP.	4	MINUS	4	0	x \$84 =	\$0
FIRST PRESENTATION OF MULTIPLE DEP CLAIMS					+ \$280	\$0
TOTAL						\$0

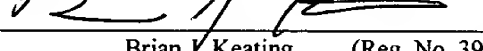
Small Entity 50% Filing Fee Reduction (if applicable) \$0

- * If the entry in Col. 1 is less than the entry in Col. 2, write "0" in Col. 3
** If the "Highest Number Previously Paid For" IN THIS SPACE is less than 20, write "20" in this space.
*** If the "Highest Number Previously Paid For" IN THIS SPACE is less than 3, write "3" in this space. The "Highest Number Previously Paid For" (Total or Independent) is the highest number found from the equivalent box in Col. 1 of a prior amendment or the number of claims originally filed.)

- ☒ No additional fee is required.
- ☐ A check in the amount of \$_____ is attached.
- ☒ Please charge any additional fees, including any fees necessary for extensions of time or credit overpayment to Deposit Account No. 50-1703, under Order No. TWI-10820.
A duplicate copy of this sheet is enclosed.
- ☒ Petition for extension of time. The undersigned attorney of record hereby petitions for an extension of time pursuant to 37 C.F.R. § 1.136(a), as may be required, to file this response.

STALLMAN & POLLOCK LLP

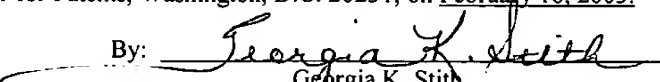
Dated: February 18, 2003

By: 
Brian J. Keating (Reg. No. 39,520)
Attorneys for Applicant(s)

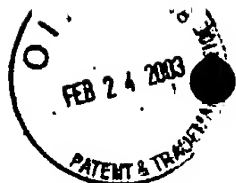
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Allan Rosencwaig et al.

Application No.: 09/629,407

Filed: August 1, 2000

For: MEASUREMENT OF THIN FILMS
AND BARRIER LAYERS ON
PATTERNED WAFERS WITH X-RAY
REFLECTOMETRY

Group Art Unit: 2876

Examiner: H.K. Song

**RESPONSE TO NOVEMBER 25, 2002
OFFICE ACTION**

121 Spear Street, Suite 290
San Francisco, CA 94105
(415) 512-1312

14 / Response
to Mark,
2.28.03
& attach

Commissioner for Patents
Washington, D.C. 20231

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STALLMAN & POLLOCK LLP

Dated: 02/18/2003

By:

Georgia K. Stith

Sir:

In response to the November 25, 2002, Office Action, the Applicants respectfully
traverse the rejections as follows.

REMARKS

The pending claims (1-31) in the above-identified application have been rejected. The Applicants respectfully traverse these rejections. Reconsideration of the above-identified application is requested in view of the remarks that follow.

The Office Action rejects independent claims 1, 11, 20 and 29 under 35 USC §102(e) as being anticipated by Komiya et al (US 6,040,198).

The specification of the present application discusses the use of a probe beam of X-rays which are directed to a sample, reflected of a sample and then the reflected X-rays are analyzed to determine properties of thin films. It is believed that prior to the system and method described

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